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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	STM8
Core Size	8-Bit
Speed	24MHz
Connectivity	I ² C, IrDA, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	38
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	6K x 8
Voltage - Supply (Vcc/Vdd)	2.95V ~ 5.5V
Data Converters	A/D 10x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	-
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8s207c6t6

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2 Description

The STM8S20xxx performance line 8-bit microcontrollers offer from 32 to 128 Kbytes Flash program memory. They are referred to as high-density devices in the STM8S microcontroller family reference manual.

All STM8S20xxx devices provide the following benefits: reduced system cost, performance robustness, short development cycles, and product longevity.

The system cost is reduced thanks to an integrated true data EEPROM for up to 300 k write/erase cycles and a high system integration level with internal clock oscillators, watchdog, and brown-out reset.

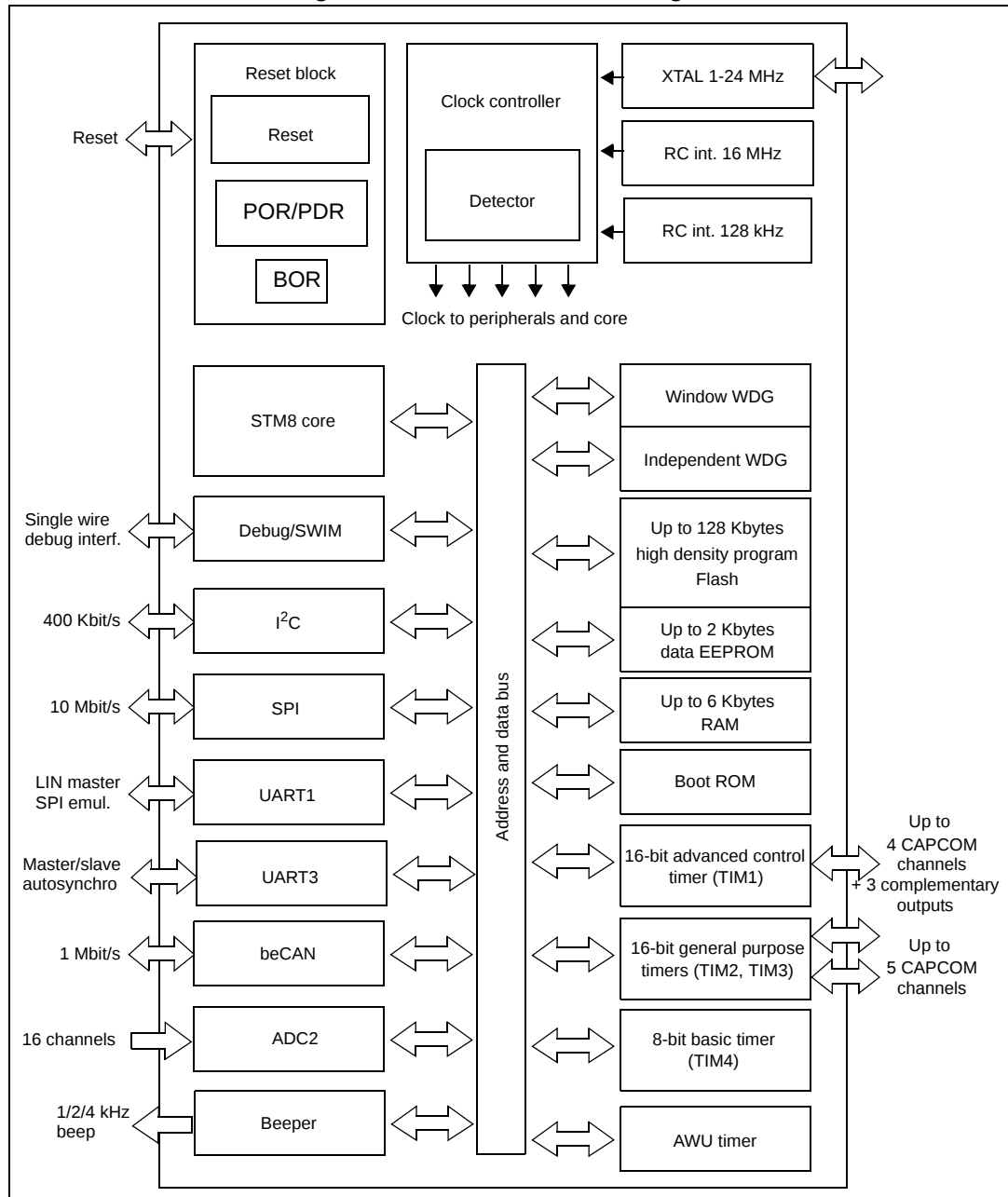
Device performance is ensured by 20 MIPS at 24 MHz CPU clock frequency and enhanced characteristics which include robust I/O, independent watchdogs (with a separate clock source), and a clock security system.

Short development cycles are guaranteed due to application scalability across a common family product architecture with compatible pinout, memory map and modular peripherals. Full documentation is offered with a wide choice of development tools.

Product longevity is ensured in the STM8S family thanks to their advanced core which is made in a state-of-the art technology for applications with 2.95 V to 5.5 V operating supply.

3 Block diagram

Figure 1. STM8S20xxx block diagram



1. Legend:
- ADC: Analog-to-digital converter
 - beCAN: Controller area network
 - BOR: Brownout reset
 - I²C: Inter-integrated circuit multimaster interface
 - Independent WDG: Independent watchdog
 - POR/PDR: Power on reset / power down reset
 - SPI: Serial peripheral interface
 - SWIM: Single wire interface module
 - UART: Universal asynchronous receiver transmitter
 - Window WDG: Window watchdog

Asynchronous communication (UART mode)

- Full duplex communication - NRZ standard format (mark/space)
- Programmable transmit and receive baud rates up to 1 Mbit/s ($f_{CPU}/16$) and capable of following any standard baud rate regardless of the input frequency
- Separate enable bits for transmitter and receiver
- Two receiver wakeup modes:
 - Address bit (MSB)
 - Idle line (interrupt)
- Transmission error detection with interrupt generation
- Parity control

LIN master capability

- Emission: Generates 13-bit sync break frame
- Reception: Detects 11-bit break frame

LIN slave mode

- Autonomous header handling - one single interrupt per valid message header
- Automatic baud rate synchronization - maximum tolerated initial clock deviation $\pm 15\%$
- Sync delimiter checking
- 11-bit LIN sync break detection - break detection always active
- Parity check on the LIN identifier field
- LIN error management
- Hot plugging support

4.14.3 SPI

- Maximum speed: 10 Mbit/s ($f_{MASTER}/2$) both for master and slave
- Full duplex synchronous transfers
- Simplex synchronous transfers on two lines with a possible bidirectional data line
- Master or slave operation - selectable by hardware or software
- CRC calculation
- 1 byte Tx and Rx buffer
- Slave/master selection input pin

Table 6. Pin description (continued)

Pin number					Pin name	Type	Input			Output				Main function (after reset)	Default alternate function	Alternate function after remap [option bit]
LQFP80	LQFP64	LQFP48	LQFP44	LQFP32			floating	wpu	Ext. interrupt	High sink	Speed	OD	PP			
69	55	39	35	-	PE1/I ² C_SCL	I/O	X		X		O1	T ⁽³⁾		Port E1	I ² C clock	
70	56	40	36	-	PE0/CLK_CCO	I/O	X	X	X	HS	O3	X	X	Port E0	Configurable clock output	
71	-	-	-	-	PI6	I/O	X	X			O1	X	X	Port I6		
72	-	-	-	-	PI7	I/O	X	X			O1	X	X	Port I7		
73	57	41	37	25	PD0/TIM3_CH2	I/O	X	X	X	HS	O3	X	X	Port D0	Timer 3 - channel 2	TIM1_BKIN [AFR3]/ CLK_CCO [AFR2]
74	58	42	38	26	PD1/SWIM ⁽⁴⁾	I/O	X	X	X	HS	O4	X	X	Port D1	SWIM data interface	
75	59	43	39	27	PD2/TIM3_CH1	I/O	X	X	X	HS	O3	X	X	Port D2	Timer 3 - channel 1	TIM2_CH3 [AFR1]
76	60	44	40	28	PD3/TIM2_CH2	I/O	X	X	X	HS	O3	X	X	Port D3	Timer 2 - channel 2	ADC_ETR [AFR0]
77	61	45	41	29	PD4/TIM2_CH1/B EEP	I/O	X	X	X	HS	O3	X	X	Port D4	Timer 2 - channel 1	BEEP output [AFR7]
78	62	46	42	30	PD5/ UART3_TX	I/O	X	X	X		O1	X	X	Port D5	UART3 data transmit	
79	63	47	43	31	PD6/ UART3_RX ⁽¹⁾	I/O	X	X	X		O1	X	X	Port D6	UART3 data receive	
80	64	48	44	32	PD7/TLI	I/O	X	X	X		O1	X	X	Port D7	Top level interrupt	TIM1_CH4 [AFR4] ⁽⁵⁾

1. The default state of UART1_RX and UART3_RX pins is controlled by the ROM bootloader. These pins are pulled up as part of the bootloader activation process and returned to the floating state before a return from the bootloader.
2. The beCAN interface is available on STM8S208xx devices only
3. In the open-drain output column, 'T' defines a true open-drain I/O (P-buffer, weak pull-up, and protection diode to V_{DD} are not implemented).
4. The PD1 pin is in input pull-up during the reset phase and after the internal reset release.
5. Available in 44-pin package only. On other packages, the AFR4 bit is reserved and must be kept at 0.

5.2 Alternate function remapping

As shown in the rightmost column of the pin description table, some alternate functions can be remapped at different I/O ports by programming one of eight AFR (alternate function

6 Memory and register map

6.1 Memory map

Figure 8. Memory map

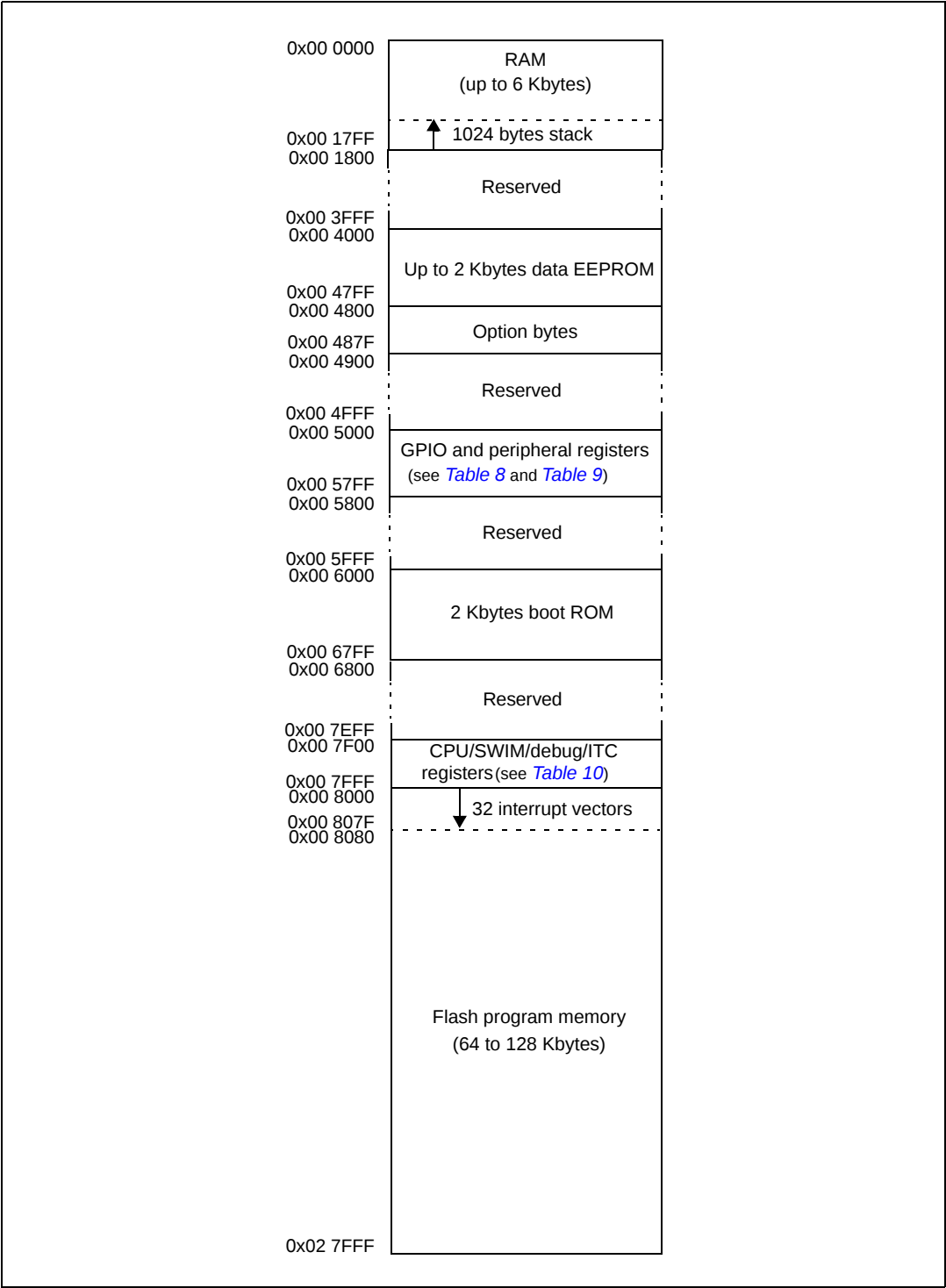


Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5216	I ² C	I2C_DR	I ² C data register	0x00
0x00 5217		I2C_SR1	I ² C status register 1	0x00
0x00 5218		I2C_SR2	I ² C status register 2	0x00
0x00 5219		I2C_SR3	I ² C status register 3	0x00
0x00 521A		I2C_ITR	I ² C interrupt control register	0x00
0x00 521B		I2C_CCRL	I ² C clock control register low	0x00
0x00 521C		I2C_CCRH	I ² C clock control register high	0x00
0x00 521D		I2C_TRISER	I ² C TRISE register	0x02
0x00 521E to 0x00 522F	Reserved area (18 bytes)			
0x00 5230	UART1	UART1_SR	UART1 status register	0xC0
0x00 5231		UART1_DR	UART1 data register	0xFF
0x00 5232		UART1_BRR1	UART1 baud rate register 1	0x00
0x00 5233		UART1_BRR2	UART1 baud rate register 2	0x00
0x00 5234		UART1_CR1	UART1 control register 1	0x00
0x00 5235		UART1_CR2	UART1 control register 2	0x00
0x00 5236		UART1_CR3	UART1 control register 3	0x00
0x00 5237		UART1_CR4	UART1 control register 4	0x00
0x00 5238		UART1_CR5	UART1 control register 5	0x00
0x00 5239		UART1_GTR	UART1 guard time register	0x00
0x00 523A		UART1_PSCR	UART1 prescaler register	0x00
0x00 523B to 0x00 523F	Reserved area (5 bytes)			
0x00 5240	UART3	UART3_SR	UART3 status register	C0h
0x00 5241		UART3_DR	UART3 data register	0xFF
0x00 5242		UART3_BRR1	UART3 baud rate register 1	0x00
0x00 5243		UART3_BRR2	UART3 baud rate register 2	0x00
0x00 5244		UART3_CR1	UART3 control register 1	0x00
0x00 5245		UART3_CR2	UART3 control register 2	0x00
0x00 5246		UART3_CR3	UART3 control register 3	0x00
0x00 5247		UART3_CR4	UART3 control register 4	0x00
0x00 5248		Reserved		
0x00 5249		UART3_CR6	UART3 control register 6	0x00
0x00 524A to 0x00 524F	Reserved area (6 bytes)			

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5250	TIM1	TIM1_CR1	TIM1 control register 1	0x00
0x00 5251		TIM1_CR2	TIM1 control register 2	0x00
0x00 5252		TIM1_SMCR	TIM1 slave mode control register	0x00
0x00 5253		TIM1_ETR	TIM1 external trigger register	0x00
0x00 5254		TIM1_IER	TIM1 Interrupt enable register	0x00
0x00 5255		TIM1_SR1	TIM1 status register 1	0x00
0x00 5256		TIM1_SR2	TIM1 status register 2	0x00
0x00 5257		TIM1_EGR	TIM1 event generation register	0x00
0x00 5258		TIM1_CCMR1	TIM1 capture/compare mode register 1	0x00
0x00 5259		TIM1_CCMR2	TIM1 capture/compare mode register 2	0x00
0x00 525A		TIM1_CCMR3	TIM1 capture/compare mode register 3	0x00
0x00 525B		TIM1_CCMR4	TIM1 capture/compare mode register 4	0x00
0x00 525C		TIM1_CCER1	TIM1 capture/compare enable register 1	0x00
0x00 525D		TIM1_CCER2	TIM1 capture/compare enable register 2	0x00
0x00 525E		TIM1_CNTRH	TIM1 counter high	0x00
0x00 525F		TIM1_CNTRL	TIM1 counter low	0x00
0x00 5260		TIM1_PSCRH	TIM1 prescaler register high	0x00
0x00 5261		TIM1_PSCRL	TIM1 prescaler register low	0x00
0x00 5262		TIM1_ARRH	TIM1 auto-reload register high	0xFF
0x00 5263		TIM1_ARRL	TIM1 auto-reload register low	0xFF
0x00 5264		TIM1_RCR	TIM1 repetition counter register	0x00
0x00 5265		TIM1_CCR1H	TIM1 capture/compare register 1 high	0x00
0x00 5266		TIM1_CCR1L	TIM1 capture/compare register 1 low	0x00
0x00 5267		TIM1_CCR2H	TIM1 capture/compare register 2 high	0x00
0x00 5268		TIM1_CCR2L	TIM1 capture/compare register 2 low	0x00
0x00 5269		TIM1_CCR3H	TIM1 capture/compare register 3 high	0x00
0x00 526A		TIM1_CCR3L	TIM1 capture/compare register 3 low	0x00
0x00 526B		TIM1_CCR4H	TIM1 capture/compare register 4 high	0x00
0x00 526C		TIM1_CCR4L	TIM1 capture/compare register 4 low	0x00
0x00 526D		TIM1_BKR	TIM1 break register	0x00
0x00 526E		TIM1_DTR	TIM1 dead-time register	0x00
0x00 526F		TIM1_OISR	TIM1 output idle state register	0x00
0x00 5270 to 0x00 52FF	Reserved area (147 bytes)			

9 Unique ID

The devices feature a 96-bit unique device identifier which provides a reference number that is unique for any device and in any context. The 96 bits of the identifier can never be altered by the user.

The unique device identifier can be read in single bytes and may then be concatenated using a custom algorithm.

The unique device identifier is ideally suited:

- For use as serial numbers
- For use as security keys to increase the code security in the program memory while using and combining this unique ID with software cryptographic primitives and protocols before programming the internal memory.
- To activate secure boot processes

Table 14. Unique ID registers (96 bits)

Address	Content description	Unique ID bits							
		7	6	5	4	3	2	1	0
0x48CD	X co-ordinate on the wafer	U_ID[7:0]							
0x48CE		U_ID[15:8]							
0x48CF	Y co-ordinate on the wafer	U_ID[23:16]							
0x48D0		U_ID[31:24]							
0x48D1	Wafer number	U_ID[39:32]							
0x48D2	Lot number	U_ID[47:40]							
0x48D3		U_ID[55:48]							
0x48D4		U_ID[63:56]							
0x48D5		U_ID[71:64]							
0x48D6		U_ID[79:72]							
0x48D7		U_ID[87:80]							
0x48D8		U_ID[95:88]							

10.2 Absolute maximum ratings

Stresses above those listed as 'absolute maximum ratings' may cause permanent damage to the device. This is a stress rating only and functional operation of the device under these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 15. Voltage characteristics

Symbol	Ratings	Min	Max	Unit
$V_{DDX} - V_{SS}$	Supply voltage (including V_{DDA} and V_{DDIO}) ⁽¹⁾	-0.3	6.5	V
V_{IN}	Input voltage on true open drain pins (PE1, PE2) ⁽²⁾	$V_{SS} - 0.3$	6.5	
	Input voltage on any other pin ⁽²⁾	$V_{SS} - 0.3$	$V_{DD} + 0.3$	
$ V_{DDX} - V_{DD} $	Variations between different power pins		50	mV
$ V_{SSX} - V_{SS} $	Variations between all the different ground pins		50	
V_{ESD}	Electrostatic discharge voltage	see Absolute maximum ratings (electrical sensitivity) on page 89		

1. All power (V_{DD} , V_{DDIO} , V_{DDA}) and ground (V_{SS} , V_{SSIO} , V_{SSA}) pins must always be connected to the external power supply
2. $I_{INJ(PIN)}$ must never be exceeded. This is implicitly insured if V_{IN} maximum is respected. If V_{IN} maximum cannot be respected, the injection current must be limited externally to the $I_{INJ(PIN)}$ value. A positive injection is induced by $V_{IN} > V_{DD}$ while a negative injection is induced by $V_{IN} < V_{SS}$. For true open-drain pads, there is no positive injection current, and the corresponding V_{IN} maximum must always be respected

Total current consumption in active halt mode

Table 24. Total current consumption in active halt mode at $V_{DD} = 5\text{ V}$, $T_A -40$ to 85°C

Symbol	Parameter	Conditions			Typ	Max ⁽¹⁾	Unit
		Main voltage regulator (MVR) ⁽²⁾	Flash mode ⁽³⁾	Clock source			
$I_{DD(AH)}$	Supply current in active halt mode	On	Operating mode	HSE crystal oscillator (16 MHz)	1000		μA
				LSI RC oscillator (128 kHz)	200	260	
			Power-down mode	HSE crystal oscillator (16 MHz)	940		
				LSI RC oscillator (128 kHz)	140		
		Off	Operating mode	LSI RC oscillator 128 kHz)	68		
			Power-down mode		11	45	

1. Data based on characterization results, not tested in production.

2. Configured by the REGAH bit in the CLK_IKCR register.

3. Configured by the AHALT bit in the FLASH_CR1 register.

Table 25. Total current consumption in active halt mode at $V_{DD} = 3.3\text{ V}$

Symbol	Parameter	Conditions			Typ ⁽¹⁾	Unit
		Main voltage regulator (MVR) ⁽²⁾	Flash mode ⁽³⁾	Clock source		
$I_{DD(AH)}$	Supply current in active halt mode	On	Operating mode	HSE crystal osc. (16 MHz)	600	μA
				LSI RC osc. (128 kHz)	200	
			Power-down mode	HSE crystal osc. (16 MHz)	540	
				LSI RC osc. (128 kHz)	140	
		Off	Operating mode	LSI RC osc. (128 kHz)	66	
			Power-down mode		9	

1. Data based on characterization results, not tested in production.

2. Configured by the REGAH bit in the CLK_IKCR register.

3. Configured by the AHALT bit in the FLASH_CR1 register.

Total current consumption in halt mode**Table 26. Total current consumption in halt mode at $V_{DD} = 5\text{ V}$**

Symbol	Parameter	Conditions	Typ	Max at 85 °C	Max at 125 °C	Unit
$I_{DD(H)}$	Supply current in halt mode	Flash in operating mode, HSI clock after wakeup	63.5			μA
		Flash in power-down mode, HSI clock after wakeup	6.5	35	100	

Table 27. Total current consumption in halt mode at $V_{DD} = 3.3\text{ V}$

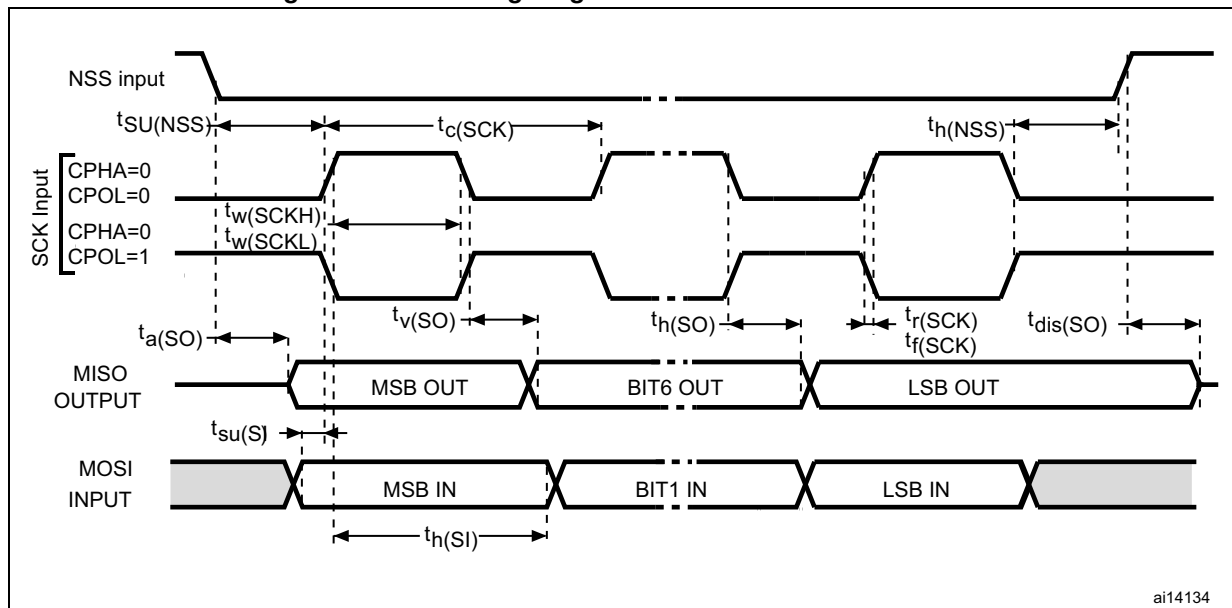
Symbol	Parameter	Conditions	Typ	Unit
$I_{DD(H)}$	Supply current in halt mode	Flash in operating mode, HSI clock after wakeup	61.5	μA
		Flash in power-down mode, HSI clock after wakeup	4.5	

Low power mode wakeup times**Table 28. Wakeup times**

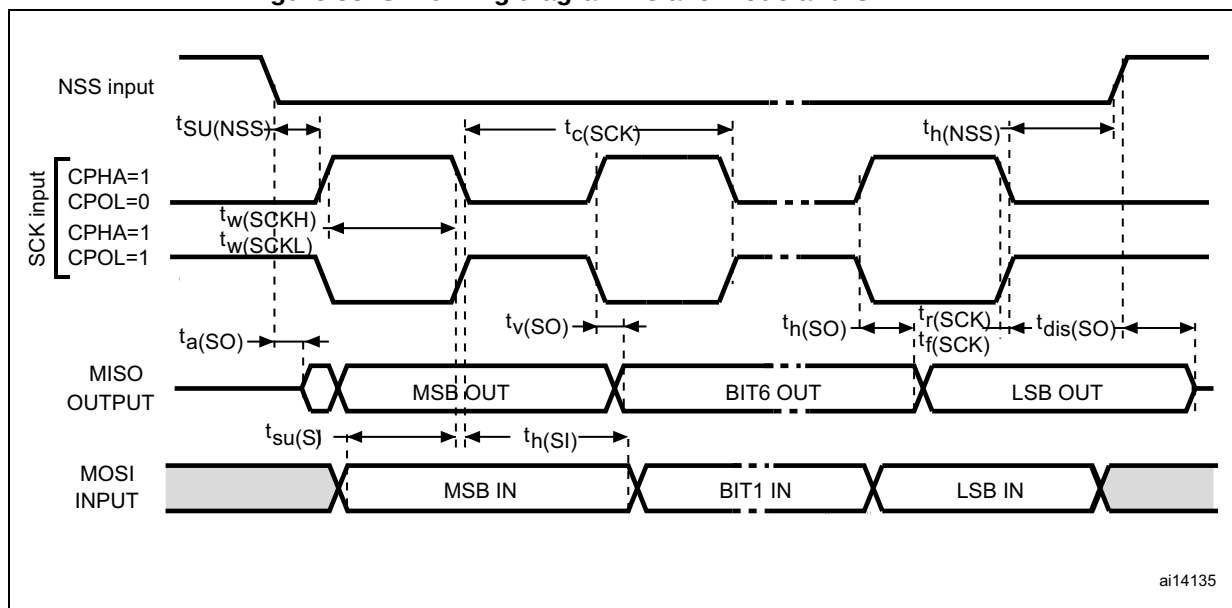
Symbol	Parameter	Conditions		Typ	Max ⁽¹⁾	Unit
$t_{WU(WFI)}$	Wakeup time from wait mode to run mode ⁽³⁾	$f_{CPU} = f_{MASTER} = 16\text{ MHz}$.		0.56	See note ⁽²⁾	μs
$t_{WU(AH)}$	Wakeup time active halt mode to run mode ⁽³⁾	MVR voltage regulator on ⁽⁴⁾	Flash in operating mode ⁽⁵⁾	1 ⁽⁶⁾	2 ⁽⁶⁾	
			Flash in power-down mode ⁽⁵⁾	3 ⁽⁶⁾		
		MVR voltage regulator off ⁽⁴⁾	Flash in operating mode ⁽⁵⁾	48 ⁽⁶⁾		
			Flash in power-down mode ⁽⁵⁾	50 ⁽⁶⁾		
$t_{WU(H)}$	Wakeup time from halt mode to run mode ⁽³⁾	Flash in operating mode ⁽⁵⁾		52		
		Flash in power-down mode ⁽⁵⁾		54		

1. Data guaranteed by design, not tested in production.
2. $t_{WU(WFI)} = 2 \times 1/f_{master} + 7 \times 1/f_{CPU}$
3. Measured from interrupt event to interrupt vector fetch.
4. Configured by the REGAH bit in the CLK_ICR register.
5. Configured by the AHALT bit in the FLASH_CR1 register.
6. Plus 1 LSI clock depending on synchronization.

Figure 37. SPI timing diagram - slave mode and CPHA = 0

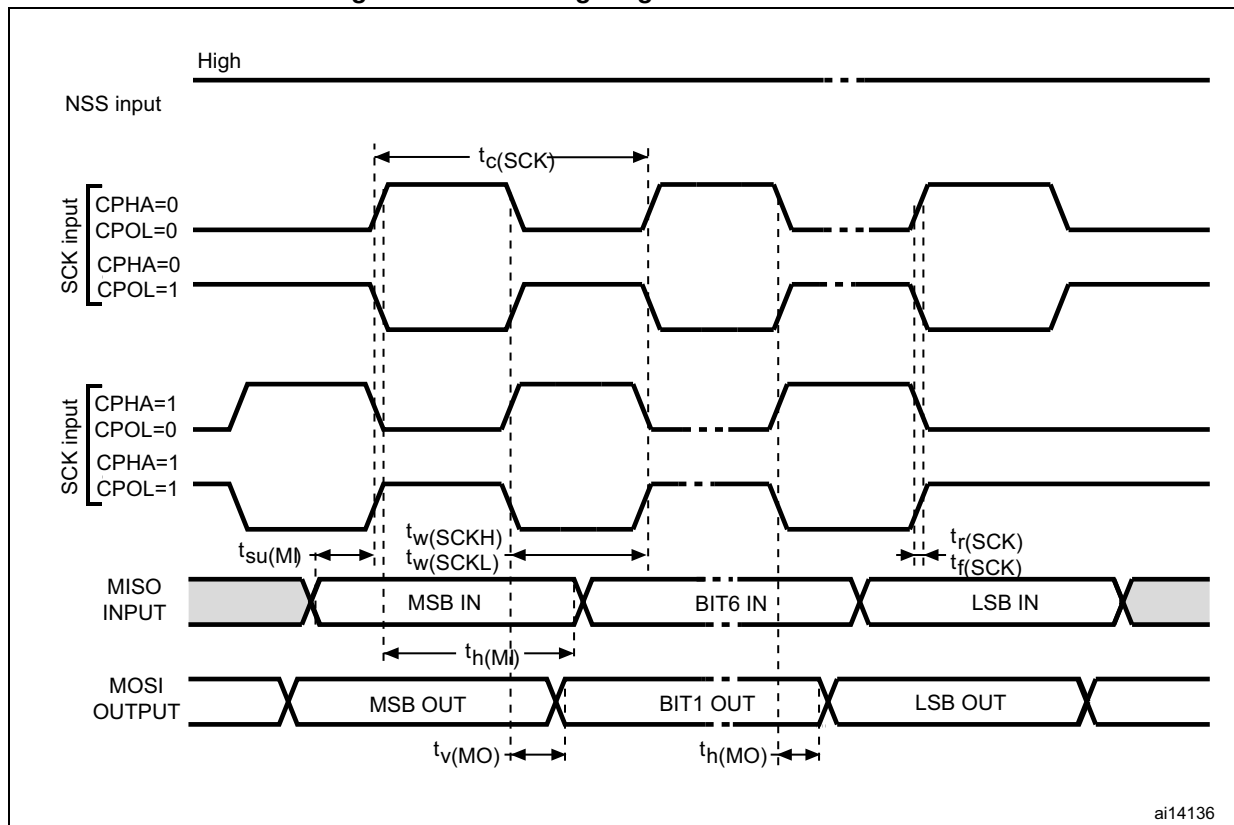


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Figure 38. SPI timing diagram - slave mode and CPHA = 1⁽¹⁾

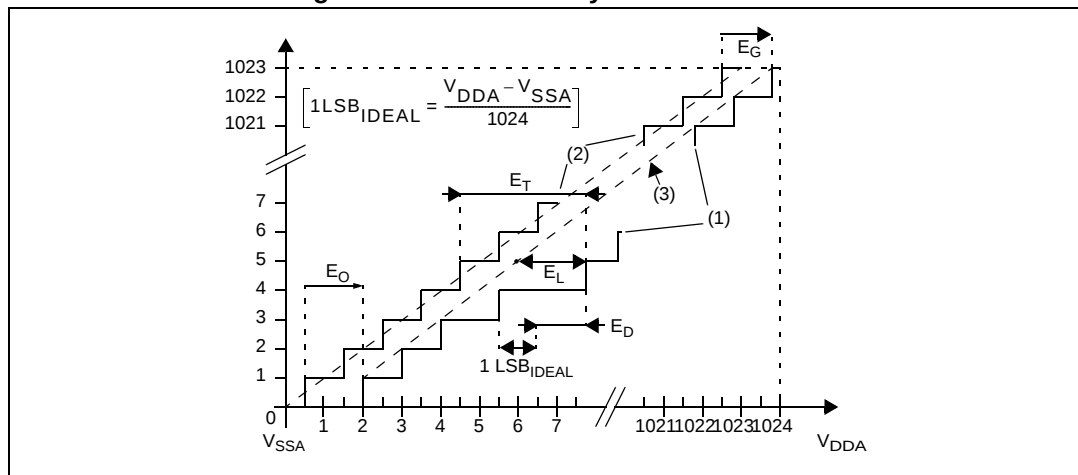
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1. Measurement points are done at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD} .

Figure 39. SPI timing diagram - master mode⁽¹⁾

1. Measurement points are done at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD} .

Figure 41. ADC accuracy characteristics



1. Example of an actual transfer curve.
 2. The ideal transfer curve
 3. End point correlation line
- E_T = Total unadjusted error: maximum deviation between the actual and the ideal transfer curves.
 E_O = Offset error: deviation between the first actual transition and the first ideal one.
 E_G = Gain error: deviation between the last ideal transition and the last actual one.
 E_D = Differential linearity error: maximum deviation between actual steps and the ideal one.
 E_L = Integral linearity error: maximum deviation between any actual transition and the end point correlation line.

Figure 42. Typical application with ADC

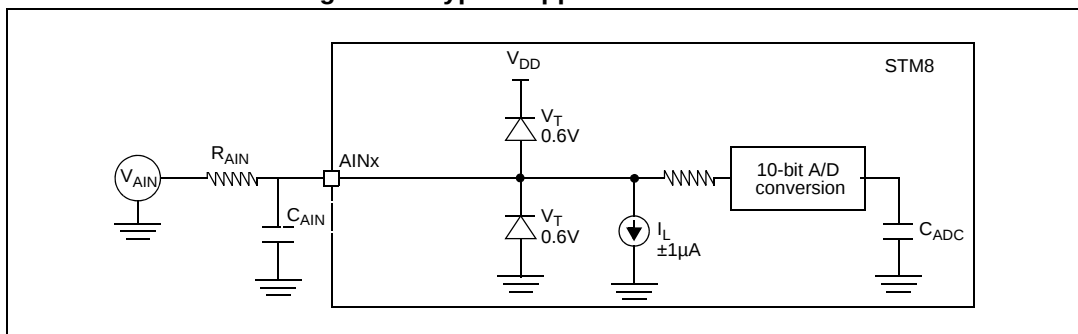
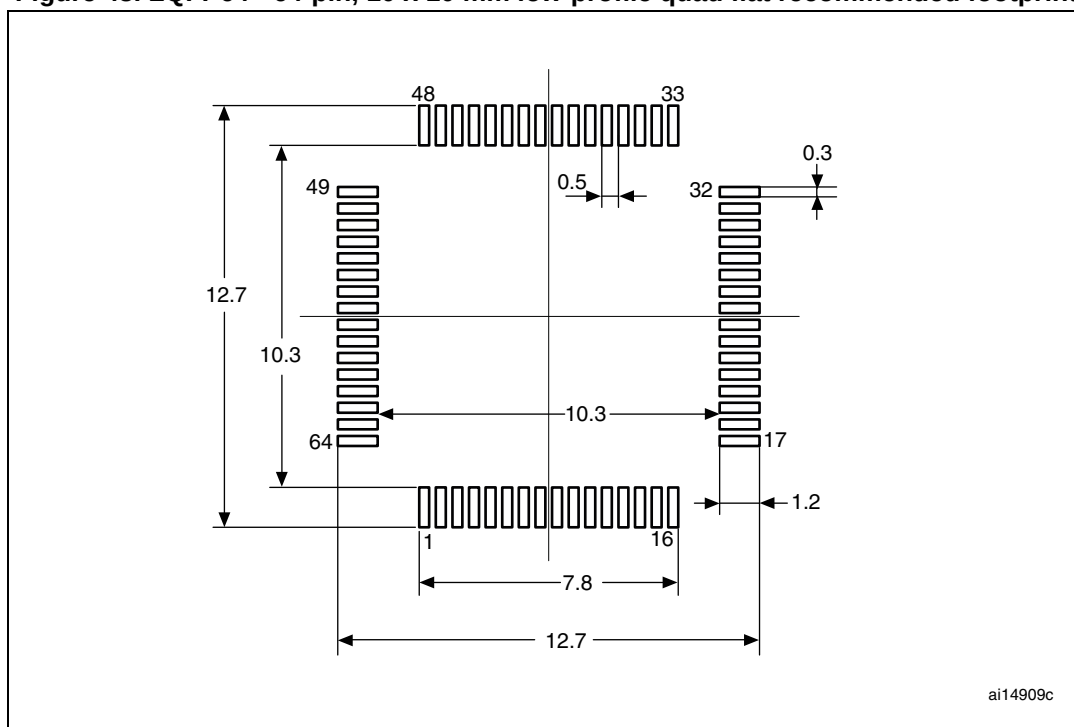


Table 53. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package mechanical data (continued)

Symbol	mm			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
D	-	12.000	-	-	0.4724	-
D1	-	10.000	-	-	0.3937	-
D3	-	7.500	-	-	0.2953	-
E	-	12.000	-	-	0.4724	-
E1	-	10.000	-	-	0.3937	-
E3	-	7.500	-	-	0.2953	-
e	-	0.500	-	-	0.0197	-
θ	0°	3.5°	7°	0°	3.5°	7°
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to four decimal places.

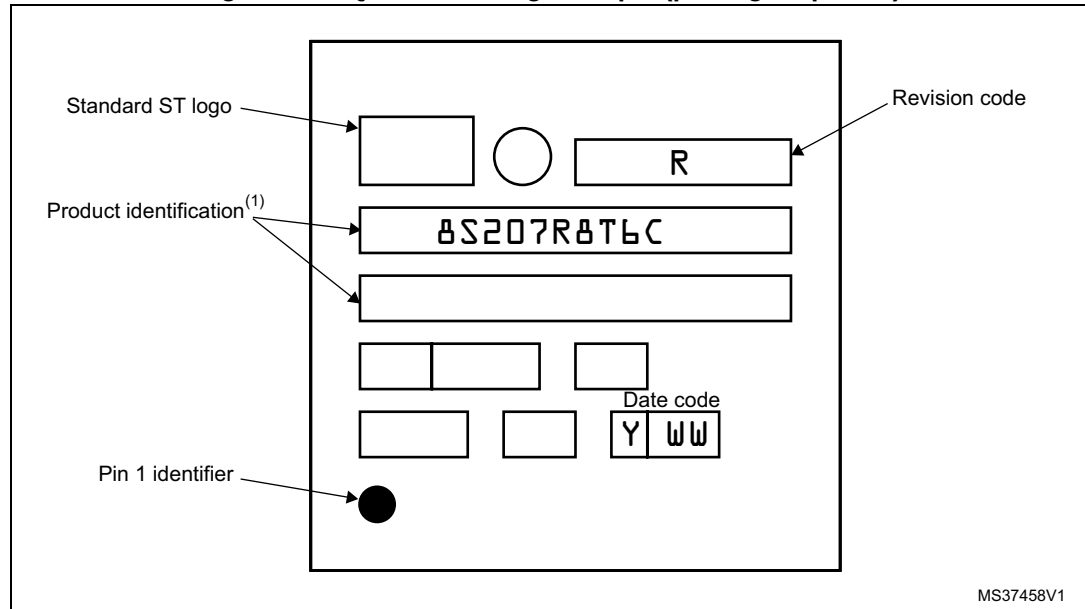
Figure 48. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat recommended footprint



Device marking

The following figure shows the marking for the LQFP64 package.

Figure 49. LQFP64 marking example (package top view)



1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

11.1.3 LQFP48 package information

Figure 50. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package outline

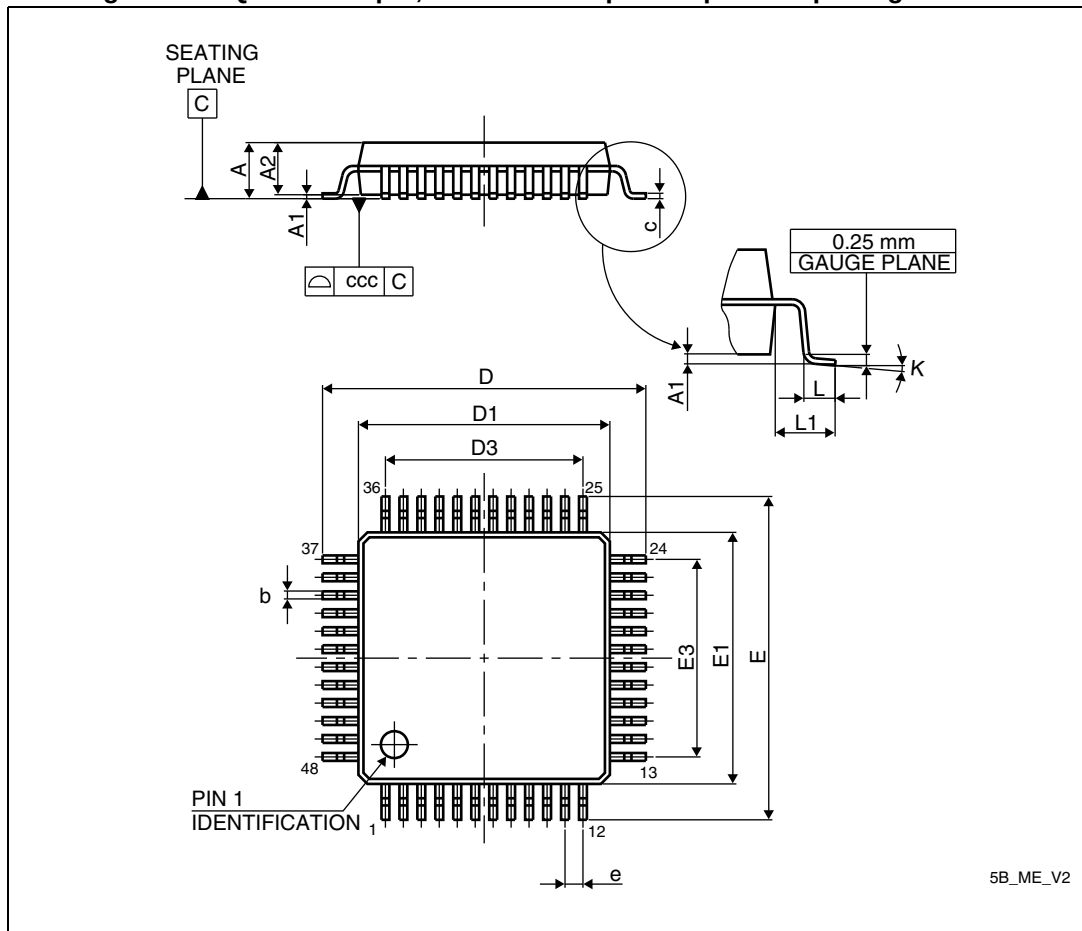


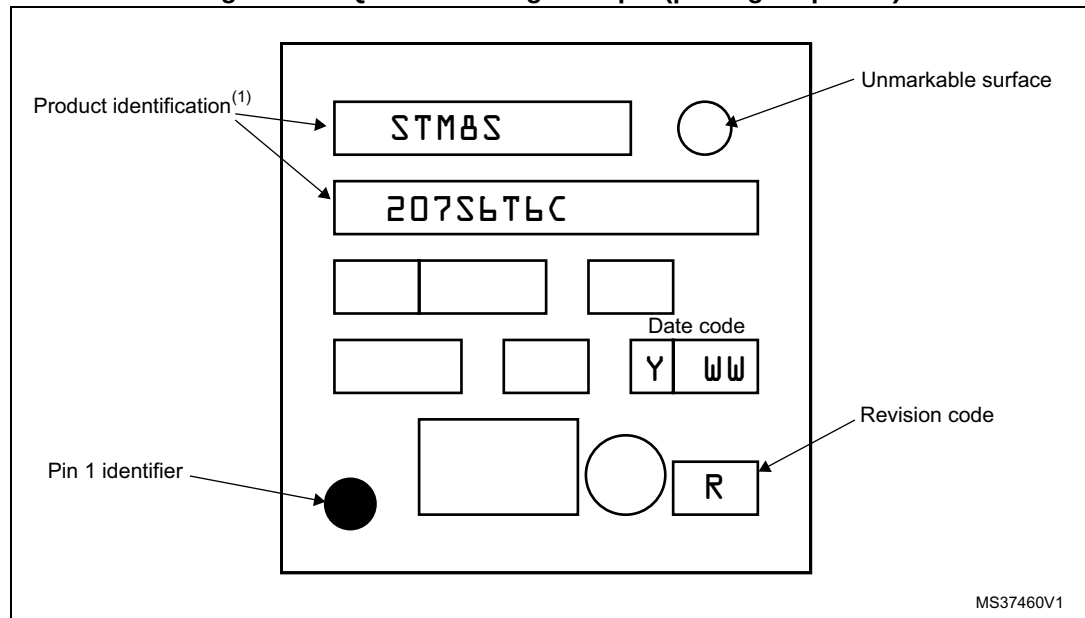
Table 54. LQFP48 - 48-pin, 7x 7 mm low-profile quad flat package mechanical

Symbol	mm			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	8.800	9.000	9.200	0.3465	0.3543	0.3622
D1	6.800	7.000	7.200	0.2677	0.2756	0.2835
D3	-	5.500	-	-	0.2165	-
E	8.800	9.000	9.200	0.3465	0.3543	0.3622

[illegible]

Device marking

Figure 55. LQFP44 marking example (package top view)

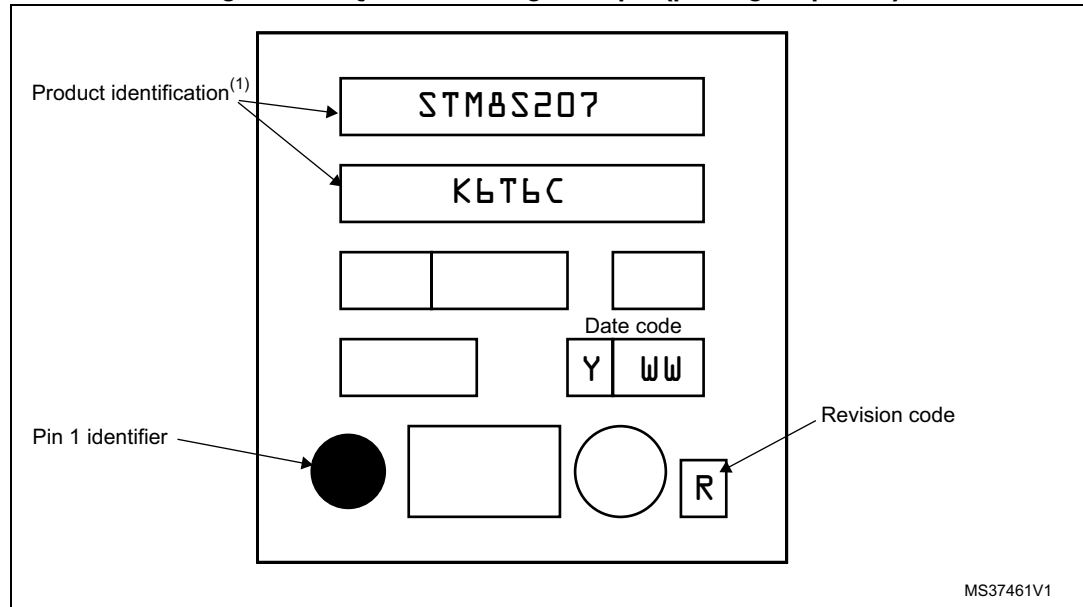


1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

Device marking

The following figure shows the marking for the LQFP32 package.

Figure 58. LQFP32 marking example (package top view)



1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.